Artificial Intelligence and Edge Computing in IoT-Based Applications

Guest Editor:

Dr. Fangmin Xu
School of Information and Communication Engineering, Beijing University of Posts and Telecommunication,100876 Beijing, China

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Message from the Guest Editor

Dear Colleagues,

The integration of edge computing along with artificial intelligence technology has great potential to gather and process large amounts of IoT data, maximize the potential for rapid, real-time data analysis and intelligent decision-making, and deliver a variety of low-latency, reliable, intelligent, and time-sensitive services.

This Special Issue aims to focus on all aspects of research relevant to artificial intelligence and edge computing technologies in IoT applications. This Special Issue invites research and review papers that report on novel contributions with respect to cloud–edge collaboration, federated learning, the utilization of a large language model (LLM), and related innovative applications within the IoT.

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Special Issue

Editor-in-Chief

Prof. Dr. Vittorio M. N. Passaro
Dipartimento di Ingegneria Elettrica e dell'Informazione (Department of Electrical and Information Engineering), Politecnico di Bari, Via Edoardo Orabona n. 4, 70125 Bari, Italy

Message from the Editor-in-Chief

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